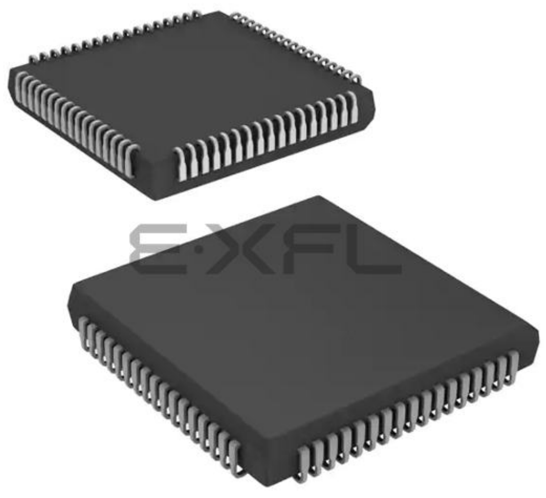

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	57
Number of Gates	3000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	68-LCC (J-Lead)
Supplier Device Package	68-PLCC (24.23x24.23)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a40mx02-1pl68m

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2.3 Ordering Information

The following figure shows ordering information.All the following tables show plastic and ceramic device resources, temperature and speed grade offerings.

Figure 1 • **Ordering Information**

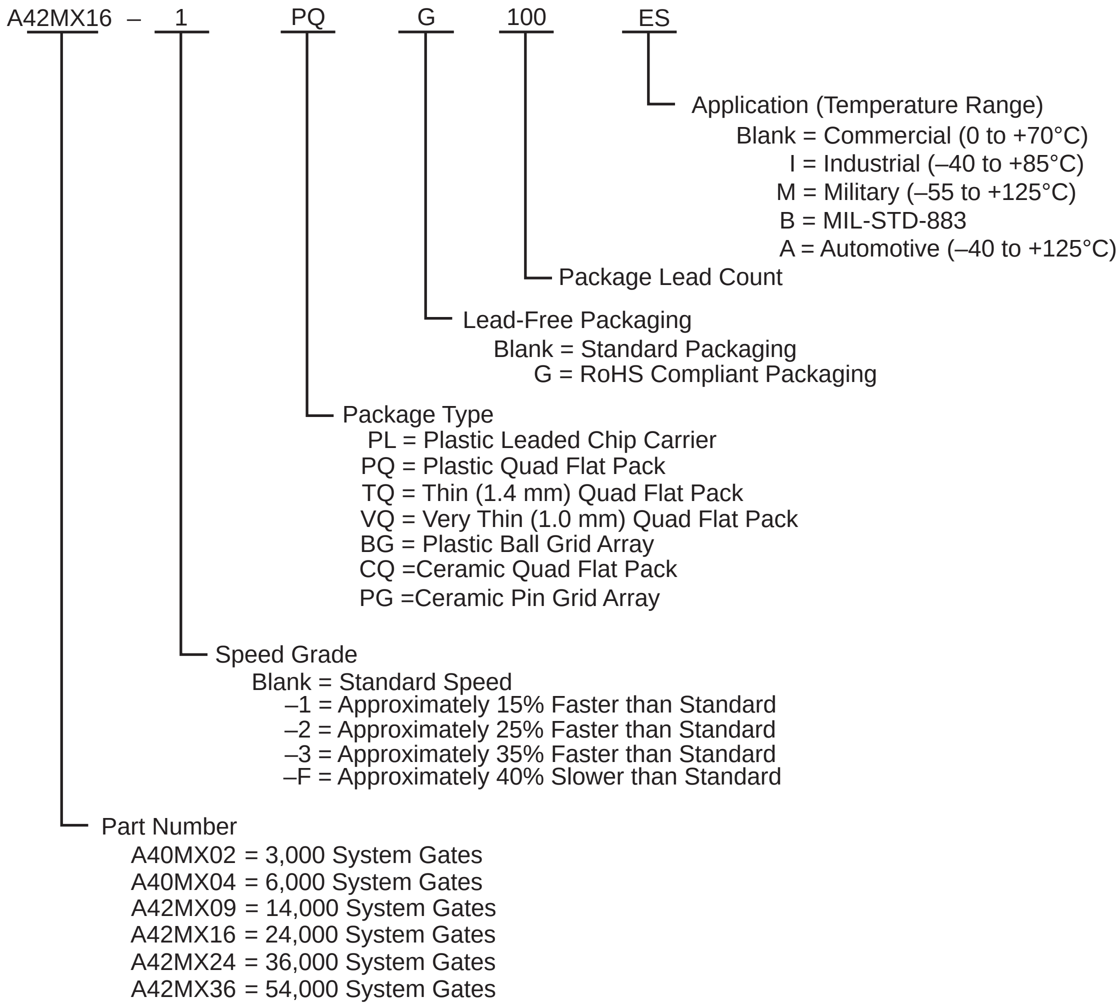
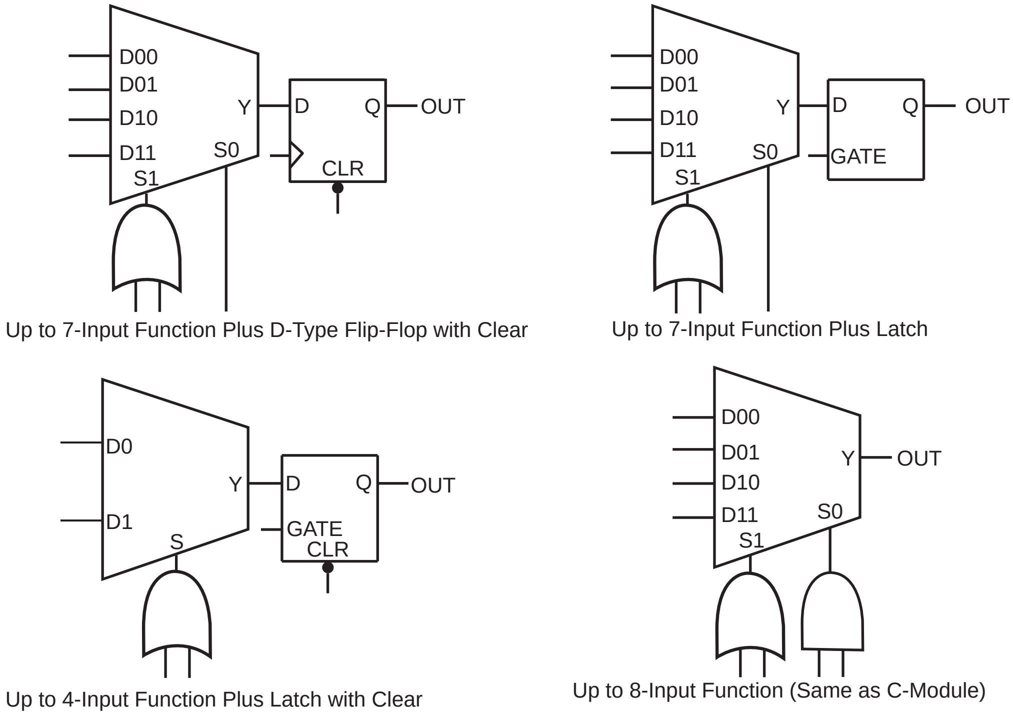


Figure 4 • **42MX S-Module Implementation**



A42MX24 and A42MX36 devices contain D-modules, which are arranged around the periphery of the device. D-modules contain wide-decode circuitry, providing a fast, wide-input AND function similar to that found in CPLD architectures (Figure 5, page 9). The D-module allows A42MX24 and A42MX36 devices to perform wide-decode functions at speeds comparable to CPLDs and PALs. The output of the D-module has a programmable inverter for active HIGH or LOW assertion. The D-module output is hardwired to an output pin, and can also be fed back into the array to be incorporated into other logic.

3.2.2 Dual-Port SRAM Modules

The A42MX36 device contains dual-port SRAM modules that have been optimized for synchronous or asynchronous applications. The SRAM modules are arranged in 256-bit blocks that can be configured as 32x8 or 64x4. SRAM modules can be cascaded together to form memory spaces of user-definable width and depth. A block diagram of the A42MX36 dual-port SRAM block is shown in Figure 6, page 9.

The A42MX36 SRAM modules are true dual-port structures containing independent read and write ports. Each SRAM module contains six bits of read and write addressing (RDAD[5:0] and WRAD[5:0], respectively) for 64x4-bit blocks. When configured in byte mode, the highest order address bits (RDAD5 and WRAD5) are not used. The read and write ports of the SRAM block contain independent clocks (RCLK and WCLK) with programmable polarities offering active HIGH or LOW implementation. The SRAM block contains eight data inputs (WD[7:0]), and eight outputs (RD[7:0]), which are connected to segmented vertical routing tracks.

The A42MX36 dual-port SRAM blocks provide an optimal solution for high-speed buffered applications requiring FIFO and LIFO queues. The ACTgen Macro Builder within Microsemi's designer software provides capability to quickly design memory functions with the SRAM blocks. Unused SRAM blocks can be used to implement registers for other user logic within the design.

Silicon Sculptor programs devices independently to achieve the fastest programming times possible. After being programmed, each fuse is verified to insure that it has been programmed correctly. Furthermore, at the end of programming, there are integrity tests that are run to ensure no extra fuses have been programmed. Not only does it test fuses (both programmed and non-programmed), Silicon Sculptor also allows self-test to verify its own hardware extensively.

The procedure for programming an MX device using Silicon Sculptor is as follows:

1. Load the *.AFM file
2. Select the device to be programmed
3. Begin programming

When the design is ready to go to production, Microsemi offers device volume-programming services either through distribution partners or via In-House Programming from the factory.

For more details on programming MX devices, see the *AC225: Programming Antifuse Devices* application note and the *Silicon Sculptor 3 Programmers User Guide*.

3.3.4 Power Supply

MX devices are designed to operate in both 5.0V and 3.3V environments. In particular, 42MX devices can operate in mixed 5.0 V/3.3 V systems. The following table describes the voltage support of MX devices.

Table 6 • **Voltage Support of MX Devices**

Device	VCC	VCCA	VCCI	Maximum Input Tolerance	Nominal Output Voltage
40MX	5.0 V	–	–	5.5 V	5.0 V
	3.3 V	–	–	3.6 V	3.3 V
42MX	–	5.0 V	5.0 V	5.5 V	5.0 V
	–	3.3 V	3.3 V	3.6 V	3.3 V
	–	5.0 V	3.3 V	5.5 V	3.3 V

For A42MX24 and A42MX36 devices the VCCA supply has to be monotonic during power up in order for the POR to issue reset to the JTAG state machine correctly. For more information, see the *AC291: 42MX Family Devices Power-Up Behavior*.

3.3.5 Power-Up/Down in Mixed-Voltage Mode

When powering up 42MX in mixed voltage mode (VCCA = 5.0 V and VCCI = 3.3 V), VCCA must be greater than or equal to VCCI throughout the power-up sequence. If VCCI exceeds VCCA during power-up, one of two things will happen:

- The input protection diode on the I/Os will be forward biased
- The I/Os will be at logical High

In either case, ICC rises to high levels. For power-down, any sequence with VCCA and VCCI can be implemented.

3.3.6 Transient Current

Due to the simultaneous random logic switching activity during power-up, a transient current may appear on the core supply (VCC). Customers must use a regulator for the VCC supply that can source a minimum of 100 mA for transient current during power-up. Failure to provide enough power can prevent the system from powering up properly and result in functional failure. However, there are no reliability concerns, since transient current is distributed across the die instead of confined to a localized spot.

Since the transient current is not due to I/O switching, its value and duration are independent of the VCCI.

f_{q2} = Average second routed array clock rate in MHz)

Table 7 • **Fixed Capacitance Values for MX FPGAs (pF)**

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See User Security, page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the “Reserve Probe Pin” is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and “Reserve Probe Pin” is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

Figure 12 • **Silicon Explorer II Setup with 40MX**

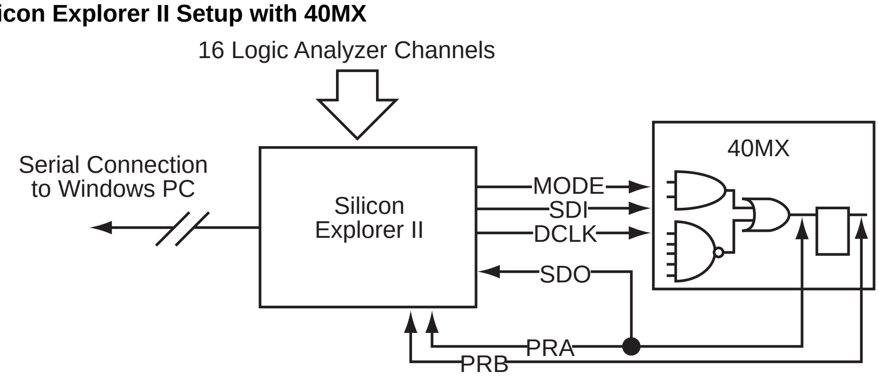
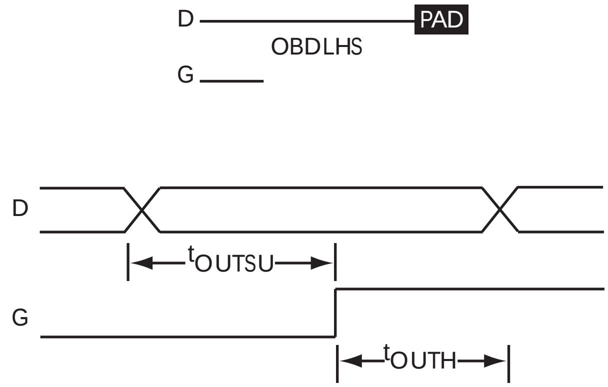


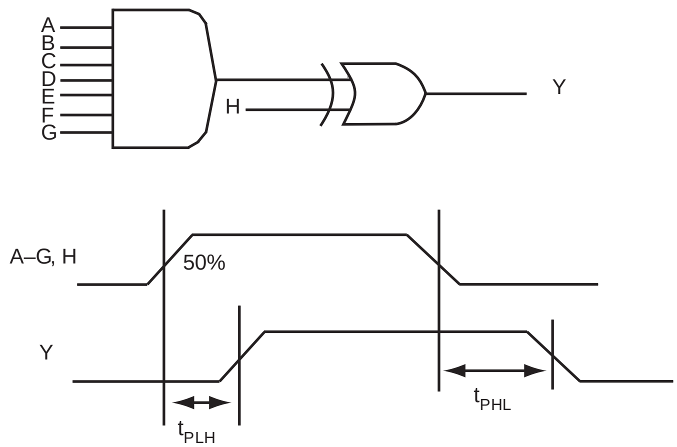
Figure 27 • **Output Buffer Latches**



3.10.4 Decode Module Timing

The following figure shows decode module timing.

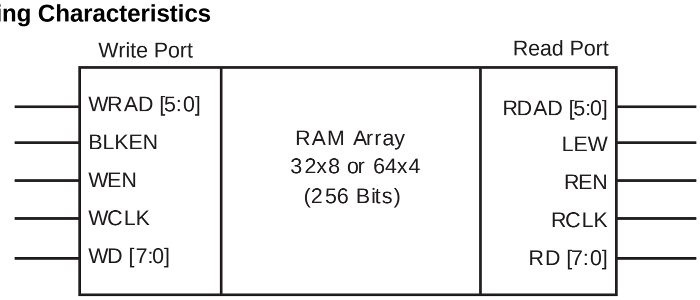
Figure 28 • **Decode Module Timing**



3.10.5 SRAM Timing Characteristics

The following figure shows SRAM timing characteristics.

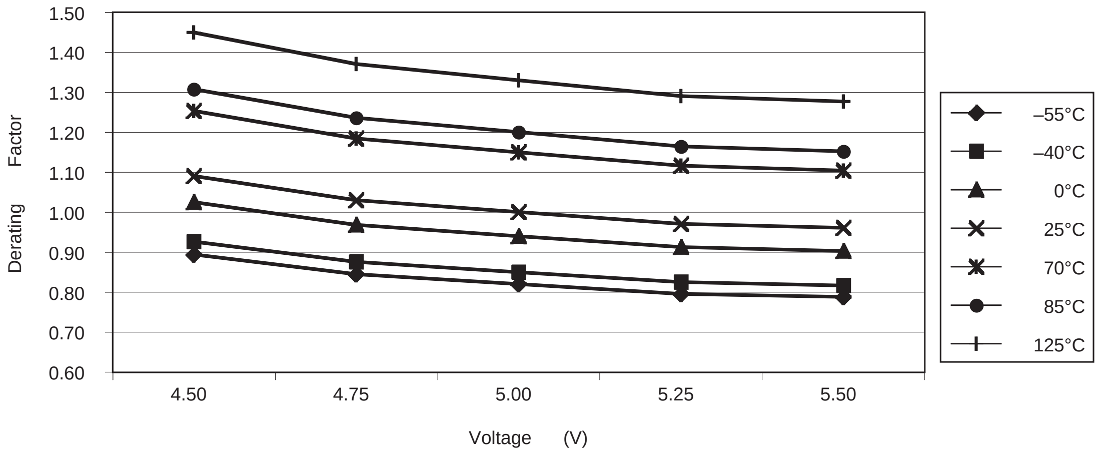
Figure 29 • **SRAM Timing Characteristics**



3.10.6 Dual-Port SRAM Timing Waveforms

The following figures show dual-port SRAM timing waveforms.

Figure 35 • **40MX Junction Temperature and Voltage Derating Curves (Normalized to TJ = 25°C, VCC = 5.0 V)**

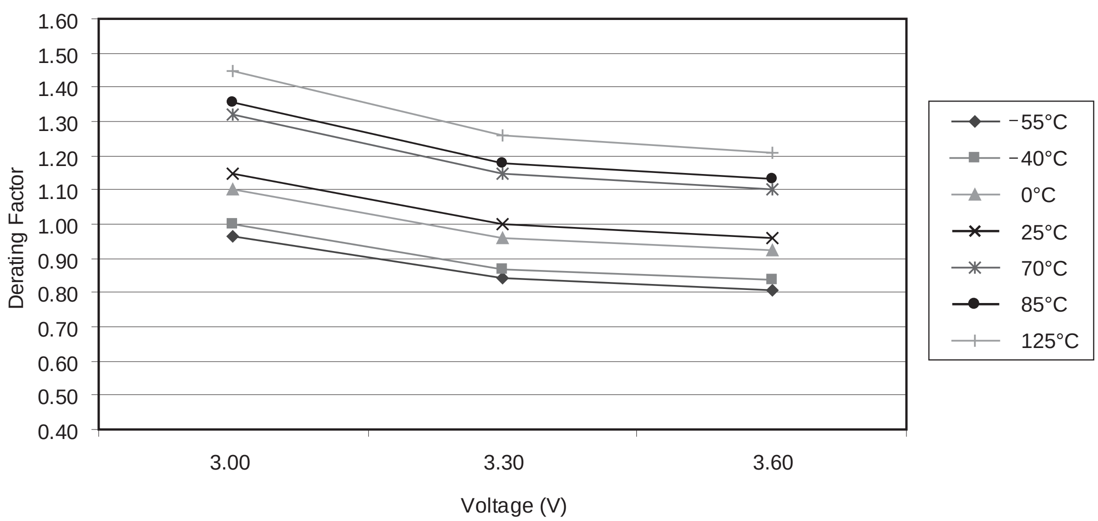


Note: This derating factor applies to all routing and propagation delays

Table 30 • **42MX Temperature and Voltage Derating Factors(Normalized to TJ = 25°C, VCCA = 3.3 V)**

	Temperature						
42MX Voltage	**–55°C**	**–40°C**	**0°C**	**25°C**	**70°C**	**85°C**	**125°C**
3.00	0.97	1.00	1.10	1.15	1.32	1.36	1.45
3.30	0.84	0.87	0.96	1.00	1.15	1.18	1.26
3.60	0.81	0.84	0.92	0.96	1.10	1.13	1.21

Figure 36 • **42MX Junction Temperature and Voltage Derating Curves (Normalized to TJ = 25°C, VCCA = 3.3 V)**



Note: This derating factor applies to all routing and propagation delays

Table 31 • **40MX Temperature and Voltage Derating Factors (Normalized to TJ = 25°C, VCC = 3.3 V)**

	Temperature						
40MX Voltage	**–55°C**	**–40°C**	**0°C**	**25°C**	**70°C**	**85°C**	**125°C**
3.00	1.08	1.12	1.21	1.26	1.50	1.64	2.00
3.30	0.86	0.89	0.96	1.00	1.19	1.30	1.59

Table 35 • A40MX02 Timing Characteristics (Nominal 3.3 V Operation) *(continued)* (Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_P	Minimum Period	FO = 16 FO = 128	6.5 6.8		7.5 7.8		8.5 8.9		10.1 10.4		14.1 14.6		ns
f_{MAX}	Maximum Frequency	FO = 16 FO = 128		113 109		105 101		96 92		83 80		50 48	MHz
TTL Output Module Timing[4]													
t_{DLH}	Data-to-Pad HIGH			4.7		5.4		6.1		7.2		10.0	ns
t_{DHL}	Data-to-Pad LOW			5.6		6.4		7.3		8.6		12.0	ns
t_{ENZH}	Enable Pad Z to HIGH			5.2		6.0		6.8		8.1		11.3	ns
t_{ENZL}	Enable Pad Z to LOW			6.6		7.6		8.6		10.1		14.1	ns
t_{ENHZ}	Enable Pad HIGH to Z			11.1		12.8		14.5		17.1		23.9	ns
t_{ENLZ}	Enable Pad LOW to Z			8.2		9.5		10.7		12.6		17.7	ns
d_{TLH}	Delta LOW to HIGH			0.03		0.03		0.04		0.04		0.06	ns/pF
d_{THL}	Delta HIGH to LOW			0.04		0.04		0.05		0.06		0.08	ns/pF

Table 35 • **A40MX02 Timing Characteristics (Nominal 3.3 V Operation) *(continued)* (Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS Output Module Timing[4]												
t_{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t_{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t_{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t_{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t_{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d_{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro
4. Delays based on 35 pF loading

Table 36 • **A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays												
t_{PD1}	Single Module		1.2		1.4		1.6		1.9		2.7	ns
t_{PD2}	Dual-Module Macros		2.3		3.1		3.5		4.1		5.7	ns
t_{CO}	Sequential Clock-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.9		2.7	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.4		1.6		1.9		2.7	ns
Logic Module Predicted Routing Delays[1]												
t_{RD1}	FO = 1 Routing Delay		1.2		1.6		1.8		2.1		3.0	ns
t_{RD2}	FO = 2 Routing Delay		1.9		2.2		2.5		2.9		4.1	ns
t_{RD3}	FO = 3 Routing Delay		2.4		2.8		3.2		3.7		5.2	ns
t_{RD4}	FO = 4 Routing Delay		2.9		3.4		3.9		4.5		6.3	ns
t_{RD8}	FO = 8 Routing Delay		5.0		5.8		6.6		7.8		10.9	ns
Logic Module Sequential Timing[2]												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	3.1		3.5		4.0		4.7		6.6		ns
t_{HD}[3]	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	3.1		3.5		4.0		4.7		6.6		ns

Table 39 • **A42MX09 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		3.4		3.8		5.5		6.4		9.0	ns
t_{DHL}	Data-to-Pad LOW		4.1		4.5		4.2		5.0		7.0	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.6		5.5		7.6	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.5		5.1		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		6.9		7.6		8.6		10.2		14.2	ns
t_{ENLZ}	Enable Pad LOW to Z		7.5		8.3		9.4		11.1		15.5	ns
t_{GLH}	G-to-Pad HIGH		5.8		6.5		7.3		8.6		12.0	ns
t_{GHL}	G-to-Pad LOW		5.8		6.5		7.3		8.6		12.0	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.7		9.7		10.9		12.9		18.0	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		12.2		13.5		15.4		18.1		25.3	ns
d_{TLH}	Capacity Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d_{THL}	Capacity Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. *For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.*
3. *Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.*
4. *Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.*
5. *Delays based on 35 pF loading.*

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.4		1.5		1.7		2.0		2.8	ns
t_{CO}	Sequential Clock-to-Q		1.4		1.6		1.8		2.1		3.0	ns
t_{GO}	Latch G-to-Q		1.4		1.5		1.7		2.0		2.8	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.6		1.7		2.0		2.3		3.3	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.8		0.9		1.0		1.2		1.6	ns
t_{RD2}	FO = 2 Routing Delay		1.0		1.2		1.3		1.5		2.1	ns

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
t_{RD3}	FO = 3 Routing Delay			1.3		1.4		1.6		1.9		2.7	ns
t_{RD4}	FO = 4 Routing Delay			1.6		1.7		2.0		2.3		3.2	ns
t_{RD8}	FO = 8 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
Logic Module Sequential Timing[3,4]													
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.3		0.4		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up		0.7		0.8		0.9		1.0		1.4		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		3.4		3.8		4.3		5.0		7.1		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		4.5		5.0		5.6		6.6		9.2		ns
t_A	Flip-Flop Clock Input Period		6.8		7.6		8.6		10.1		14.1		ns
t_{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Buffer Latch Set-Up		0.5		0.5		0.6		0.7		1.0		ns
t_{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{OUTSU}	Output Buffer Latch Set-Up		0.5		0.5		0.6		0.7		1.0		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency			215		195		179		156		94	MHz
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			1.1		1.2		1.3		1.6		2.2	ns
t_{INYL}	Pad-to-Y LOW			0.8		0.9		1.0		1.2		1.7	ns
t_{INGH}	G to Y HIGH			1.4		1.6		1.8		2.1		2.9	ns
t_{INGL}	G to Y LOW			1.4		1.6		1.8		2.1		2.9	ns
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			1.8		2.0		2.3		2.7		4.0	ns
t_{IRD2}	FO = 2 Routing Delay			2.1		2.3		2.6		3.1		4.3	ns
t_{IRD3}	FO = 3 Routing Delay			2.3		2.6		3.0		3.5		4.9	ns
t_{IRD4}	FO = 4 Routing Delay			2.6		3.0		3.3		3.9		5.4	ns
t_{IRD8}	FO = 8 Routing Delay			3.6		4.0		4.6		5.4		7.5	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32 FO = 384		2.6 2.9		2.9 3.2		3.3 3.6		3.9 4.3		5.4 6.0	ns ns
t_{CKL}	Input HIGH to LOW	FO = 32 FO = 384		3.8 4.5		4.2 5.0		4.8 5.6		5.6 6.6		7.8 9.2	ns ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 384	3.2 3.7		3.5 4.1		4.0 4.6		4.7 5.4		6.6 7.6		ns ns

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description			–3 Speed Min.	–3 Speed Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std Speed Min.	Std Speed Max.	–F Speed Min.	–F Speed Max.	Units
t_{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6		ns
		FO = 384	3.7		4.1		4.6		5.4		7.6		ns
t_{CKSW}	Maximum Skew	FO = 32		0.3		0.4		0.4		0.5		0.7	ns
		FO = 384		0.3		0.4		0.4		0.5		0.7	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7		ns
		FO = 384	3.2		3.5		4.0		4.7		6.6		ns
t_P	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7		ns
		FO = 384	4.6		5.1		5.6		6.4		10.7		ns
f_{MAX}	Maximum Frequency	FO = 32		237		215		198		172		103	MHz
		FO = 384		215		195		179		156		94	MHz

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Sequential Timing[3, 4]													
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up		0.5		0.5		0.6		0.7		0.9		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up		1.0		1.1		1.2		1.4		2.0		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width		4.8		5.3		6.0		7.1		9.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width		6.2		6.9		7.9		9.2		12.9		ns
t_A	Flip-Flop Clock Input Period		9.5		10.6		12.0		14.1		19.8		ns
t_{INH}	Input Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Buffer Latch Set-Up		0.7		0.8		0.9		1.01		1.4		ns
t_{OUTH}	Output Buffer Latch Hold		0.0		0.0		0.0		0.0		0.0		ns
t_{OUTSU}	Output Buffer Latch Set-Up		0.7		0.8		0.89		1.01		1.4		ns
f_{MAX}	Flip-Flop (Latch) Clock Frequency			129		117		108		94		56	MHz
Input Module Propagation Delays													
t_{INYH}	Pad-to-Y HIGH			1.5		1.6		1.9		2.2		3.1	ns
t_{INYL}	Pad-to-Y LOW			1.1		1.3		1.4		1.7		2.4	ns
t_{INGH}	G to Y HIGH			2.0		2.2		2.5		2.9		4.1	ns
t_{INGL}	G to Y LOW			2.0		2.2		2.5		2.9		4.1	ns
Input Module Predicted Routing Delays[2]													
t_{IRD1}	FO = 1 Routing Delay			2.6		2.9		3.2		3.8		5.3	ns
t_{IRD2}	FO = 2 Routing Delay			2.9		3.2		3.7		4.3		6.1	ns
t_{IRD3}	FO = 3 Routing Delay			3.3		3.6		4.1		4.9		6.8	ns
t_{IRD4}	FO = 4 Routing Delay			3.6		4.0		4.6		5.4		7.6	ns
t_{IRD8}	FO = 8 Routing Delay			5.1		5.6		6.4		7.5		10.5	ns
Global Clock Network													
t_{CKH}	Input LOW to HIGH	FO = 32 FO = 384		4.4 4.8		4.8 5.3		5.5 6.0		6.5 7.1		9.0 9.9	ns ns
t_{CKL}	Input HIGH to LOW	FO = 32 FO = 384		5.3 6.2		5.9 6.9		6.7 7.9		7.8 9.2		11.0 12.9	ns ns
t_{PWH}	Minimum Pulse Width HIGH	FO = 32 FO = 384	5.7 6.6		6.3 7.4		7.1 8.3		8.4 9.8		11.8 13.7		ns ns

Table 44 • **A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions[1]												
t_{PD}	Internal Array Module Delay		1.3		1.5		1.7		2.0		2.7	ns
t_{PDD}	Internal Decode Module Delay		1.6		1.8		2.0		2.4		3.3	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.2		1.4		2.0	ns
t_{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t_{RD3}	FO =3 Routing Delay		1.6		1.8		2.0		2.4		3.4	ns
t_{RD4}	FO = 4 Routing Delay		2.0		2.2		2.5		2.9		4.1	ns
t_{RD5}	FO = 8 Routing Delay		3.3		3.7		4.2		4.9		6.9	ns
t_{RDD}	Decode-to-Output Routing Delay		0.3		0.4		0.4		0.5		0.7	ns
Logic Module Sequential Timing[3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.3		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		1.6		1.7		2.0		2.3		3.2	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.5		6.4		9.0		ns
Synchronous SRAM Operations												
t_{RC}	Read Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{WC}	Write Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{RCKHL}	Clock HIGH/LOW Time	3.4		3.8		4.3		5.0		7.0		ns
t_{RCO}	Data Valid After Clock HIGH/LOW		3.4		3.8		4.3		5.0		7.0	ns
t_{ADSU}	Address/Data Set-Up Time	1.6		1.8		2.0		2.4		3.4		ns
Synchronous SRAM Operations (continued)												
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.6		0.7		0.8		0.9		1.3		ns
t_{RENH}	Read Enable Hold	3.4		3.8		4.3		5.0		7.0		ns
t_{WENSU}	Write Enable Set-Up	2.7		3.0		3.4		4.0		5.6		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	2.8		3.1		3.5		4.1		5.7		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Synchronous SRAM Operations (continued)												
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.9		1.0		1.1		1.3		1.8		ns
t_{RENH}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t_{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	3.9		4.3		4.9		5.7		8.0		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
Asynchronous SRAM Operations												
t_{RPD}	Asynchronous Access Time		11.3		12.6		14.3		16.8		23.5	ns
t_{RDADV}	Read Address Valid	12.3		13.7		15.5		18.2		25.5		ns
t_{ADSU}	Address/Data Set-Up Time	2.3		2.5		2.8		3.4		4.8		ns
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSUA}	Read Enable Set-Up to Address Valid	0.9		1.0		1.1		1.3		1.8		ns
t_{RENHA}	Read Enable Hold	4.8		5.3		6.0		7.0		9.8		ns
t_{WENSU}	Write Enable Set-Up	3.8		4.2		4.8		5.6		7.8		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{DOH}	Data Out Hold Time		1.8		2.0		2.1		2.5		3.5	ns
Input Module Propagation Delays												
t_{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.1		3.0	ns
t_{INGO}	Input Latch Gate-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns

Figure 44 • **PQ208**

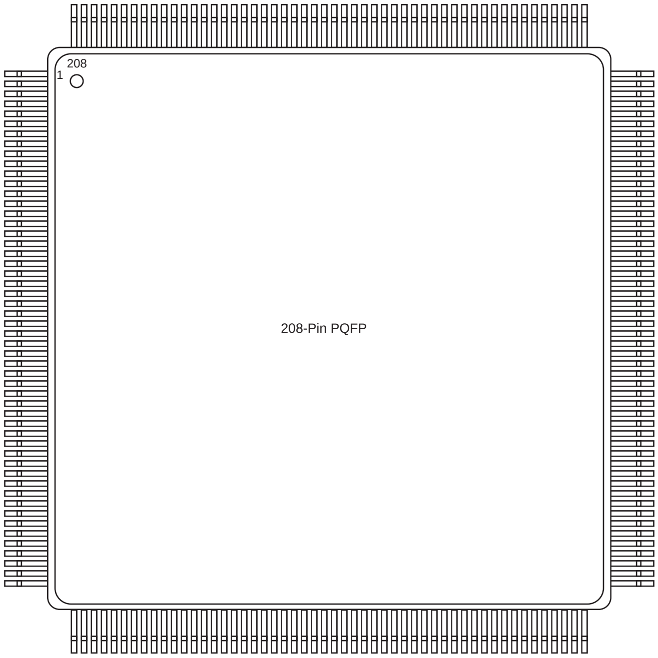


Table 53 • **PQ208**

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
1	GND	GND	GND
2	NC	VCCA	VCCA
3	MODE	MODE	MODE
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	NC	I/O	I/O
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	NC	I/O	I/O
17	VCCA	VCCA	VCCA
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O

Table 53 • PQ208

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
132	VCCI	VCCI	VCCI
133	VCCA	VCCA	VCCA
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	VCCA	VCCA	VCCA
137	I/O	I/O	I/O
138	I/O	I/O	I/O
139	I/O	I/O	I/O
140	I/O	I/O	I/O
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	I/O	I/O	I/O
146	NC	I/O	I/O
147	NC	I/O	I/O
148	NC	I/O	I/O
149	NC	I/O	I/O
150	GND	GND	GND
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	I/O	I/O	I/O
156	I/O	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	SDI, I/O	SDI, I/O	SDI, I/O
160	I/O	I/O	I/O
161	I/O	WD, I/O	WD, I/O
162	I/O	WD, I/O	WD, I/O
163	I/O	I/O	I/O
164	VCCI	VCCI	VCCI
165	NC	I/O	I/O
166	NC	I/O	I/O
167	I/O	I/O	I/O
168	I/O	WD, I/O	WD, I/O

Table 54 • **PQ240**

PQ240	
Pin Number	**A42MX36 Function**
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

Table 55 • **VQ80**

VQ80		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
13	VCC	VCC
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	NC	I/O
18	NC	I/O
19	NC	I/O
20	VCC	VCC
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	GND	GND
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	VCC	VCC
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	I/O	I/O
39	I/O	I/O
40	I/O	I/O
41	NC	I/O
42	NC	I/O
43	NC	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	GND	GND
48	I/O	I/O

Table 62 • **CQ172**

99	I/O
100	I/O
101	I/O
102	I/O
103	GND
104	I/O
105	I/O
106	VKS
107	VPP
108	GND
109	VCCI
110	VSV
111	I/O
112	I/O
113	VCC
114	I/O
115	I/O
116	I/O
117	I/O
118	GND
119	I/O
120	I/O
121	I/O
122	I/O
123	GNDI
124	I/O
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	SDI
132	I/O
133	I/O
134	I/O
135	I/O
136	VCCI
137	I/O